

P-2.1 Subcommittee on Ceramic Dielectric Capacitors

AGENDA Thursday, April 30, 2009 Chateau Bourbon Hotel New Orleans, LA

1.0 Introductions

1.1 Circulate Membership Roster

1.2 Approval of Fall Meeting Minutes from Salt Lake City, UT

1.3 Approval of Agenda for Present Meeting

1.4 Correspondence & Review of Committee's Scope

1.5 Report of task groups and committees

2.0 Old Business

2.1 Status of EIA-198-F "Ceramic Dielectric Capacitors Classes I, II, III, & IV"

2.1.1 Part III/3- standard two-terminal SMD (PN 5099)

2.1.1.1 Discussion of mechanical outlines table

2.1.1.2 Part III/6- Axial PTH (PN 5154), revision status

2.1.1.3 Part III/9- High voltage PTH & SMD, dimensions/TCVC

2.2 Ballot status on high frequency test method of low inductance MLCCs (PN 4563)

2.3 Revision status of ANSI/EIA 521 (PN 5095)

2.4 Five-year review of documents

2.4.1 EIA 198, Section 2, Test Methods

2.4.2 EIA 198, Section 3, Individual Specifications

3.0 New Business

4.0 Time and Place of next meeting

5.0 Adjournment